Notice of References Cited Application/Control No. 10/608,187 Examiner Jeff Piziali Applicant(s)/Patent Under Reexamination BAEK ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,809,719 B2	10-2004	Wu et al.	345/103
	В	US-6,747,613 B2	06-2004	Miyawaki et al.	345/9
	С	US-6,396,468 B2	05-2002	Matsushima et al.	345/87
	D	US-6,232,947 B1	05-2001	Miyawaki et al.	345/99
	E	US-6,081,250 A	06-2000	Shimada et al.	345/94
	F	US-6,067,063 A	05-2000	Kim et al.	345/89
	G	US-5,949,391 A	09-1999	Saishu et al.	345/50
	Н	US-5,805,128 A	09-1998	Kim et al.	345/96
	ı	US-5,654,733 A	08-1997	Chimura et al.	345/96
	J	US-5,436,747 A	07-1995	Suzuki, Hiroshi	349/42
	к	US-5,336,635 A	08-1994	Anayama et al.	438/40
	L	US-5,159,476 A	10-1992	Hayashi, Yuji	349/39
	М	US-4,842,371 A	06-1989	Yasuda et al.	345/96

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ø					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable:	Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U		
	٧	·	·
	w		
	x		

*A copy of this reference is not being fumished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.